
Semiconductors, Dielectrics, and Metals for Nanoelectronics 16

Preface

The papers included in this issue of *ECS Transactions* were originally presented in the symposium “Semiconductors, Dielectrics, and Metals for Nanoelectronics 16,” held during the AiMES 2018, ECS and SMEQ Joint International Meeting, in Cancun, Mexico, from September 30 – October 4, 2018. This symposium was sponsored by the Dielectric Science and Technology Division of The Electrochemical Society.

In 2005 this symposium introduced a best paper award, which has been presented every year since except for 2016. The best paper award for the “Semiconductors, Dielectrics, and Metals for Nanoelectronics 15: In Memory of Samares Kar” symposium at the 232nd ECS Meeting held in National Harbor, MD, in fall 2017 will be presented to Dr. Sinji Migita (AIST) at the AiMES 2018 meeting for his paper “Relationship between Ferroelectricity and Electrical Breakdown in Hf-Zr-O Thin Films.”

We are pleased to acknowledge the financial support from the Dielectric Science and Technology Division of The Electrochemical Society. Many thanks to the staff at ECS—especially to John Lewis, Bianca Kovalenko, and Logan Streu—for their help with the symposium and the volume.

Durga Misra
Stefan De Gendt
Shadi Dayeh
Koji Kita



Published by
The Electrochemical Society
65 South Main Street, Building D
Pennington, NJ 08534-2839, USA
tel 609 737 1902
fax 609 737 2743
www.electrochem.org

ECStransactions™

Vol. 86, No. 2